BUK6E3R4-40C

N-channel TrenchMOS intermediate level FET

Rev. 3 — 14 October 2010

Product data sheet

1. Product profile

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources
- Suitable for thermally demanding environments due to 175 ℃ rating

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{°C}; T_j \le 175 \text{°C}$		-	-	40	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ C};$ see Figure 1	[1]	-	-	100	Α
P _{tot}	total power dissipation	$T_{mb} = 25 \text{°C}$; see Figure 2		-	-	204	W
Static char	acteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ C}; \text{ see } \frac{\text{Figure 11}}{\text{ Figure 11}}$		-	3.05	3.6	mΩ



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche i	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 100 \text{ A; } V_{sup} \le 40 \text{ V;}$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V;}$ $T_{j(init)} = 25 \text{ C; unclamped}$	-	-	368	mJ
Dynamic characteristics						
Q_{GD}	gate-drain charge	I_D = 25 A; V_{DS} = 32 V; V_{GS} = 10 V; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	42	-	nC

^[1] Continuous current is limited by package.

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	Drain	mb	D
3	S	source		G (EX)
mb	D	mounting base; connected to drain	1 2 3	mbb076 S
			SOT226 (I2PAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK6E3R4-40C	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \mathbb{C}; T_j \le 175 \mathbb{C}$		-	40	V
V_{GS}	gate-source voltage	Pulsed	<u>[1]</u>	-20	20	V
		DC	[2]	-16	16	V
I _D	drain current	$T_{mb} = 25 \text{°C}; V_{GS} = 10 \text{V}; \text{see } \frac{\text{Figure 1}}{}$	[3]	-	100	Α
		$T_{mb} = 100 \text{C}$; $V_{GS} = 10 \text{V}$; see Figure 1	[3]	-	100	Α
I _{DM}	peak drain current	$T_{mb} = 25 \text{C}; t_p \le 10 \mu\text{s}; \text{ pulsed};$ see Figure 3		-	657	Α
P _{tot}	total power dissipation	$T_{mb} = 25 \text{°C}$; see Figure 2		-	204	W
T _{stg}	storage temperature			-55	175	$\mathcal C$
T_j	junction temperature			-55	175	${\mathbb C}$
Source-drain	diode					
Is	source current	T _{mb} = 25 ℃	[3]	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}\!\! C$		-	657	Α
Avalanche ruç	ggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 100 A; $V_{sup} \le$ 40 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	368	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		[4][5][6]	-	-	J

^[1] Accumulated pulse duration not to exceed 5mins.

^{[2] -16}V accumulated duration not to exceed 168 hrs.

^[3] Continuous current is limited by package.

^[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 $^{\circ}$ C.

^[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

^[6] Refer to application note AN10273 for further information.

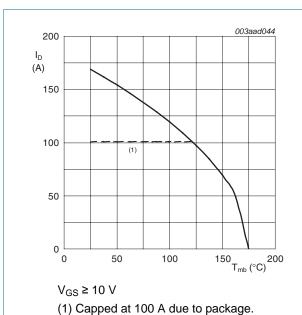


Fig 1. Continuous drain current as a function of mounting base temperature

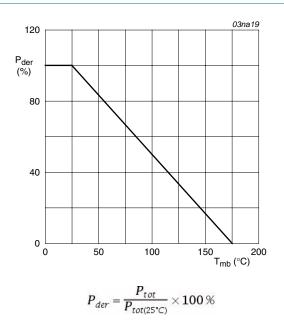
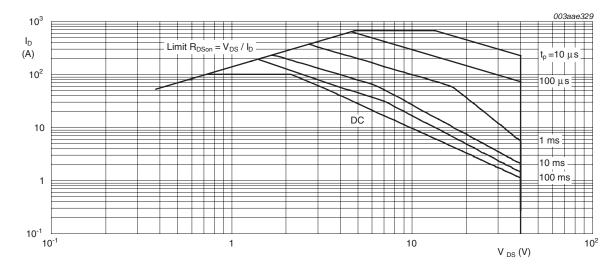


Fig 2. Normalized total power dissipation as a function of mounting base temperature



T_{mb} = 25 ℃; I_{DM} is a single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.74	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W

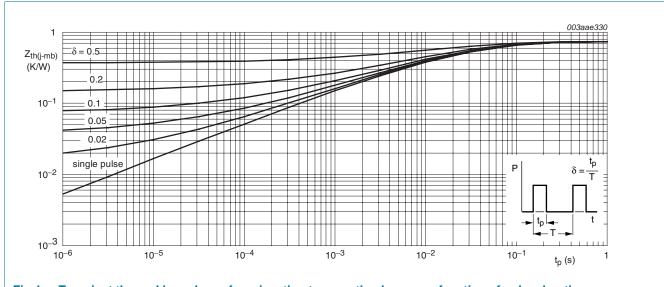


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	40	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 \degree C$	36	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see Figure 10	-	-	3.3	V
		I_D = 2.5 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 10</u>	0.8	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	500	μΑ
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.02	1	μΑ
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ C};$ see <u>Figure 11</u>	-	3.05	3.6	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ C};$ see Figure 11	-	4.2	5.3	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ C};$ see <u>Figure 11</u>	-	4.5	6	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	7.6	mΩ
Dynamic	characteristics					
Q _{G(tot)} total gate charge		$I_D = 25 \text{ A}$; $V_{DS} = 32 \text{ V}$; $V_{GS} = 10 \text{ V}$; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	125	-	nC
		$I_D = 25 \text{ A}$; $V_{DS} = 32 \text{ V}$; $V_{GS} = 5 \text{ V}$; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	- 71 -	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}$; $V_{DS} = 32 \text{ V}$; $V_{GS} = 10 \text{ V}$;	-	23	-	nC
Q_{GD}	gate-drain charge	see Figure 13; see Figure 14	-	42	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	6016	8020	pF
C _{oss}	output capacitance	$T_j = 25 \text{°C}$; see Figure 15	-	739	870	pF
C _{rss}	reverse transfer capacitance		-	510	700	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	40	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega$	-	87	-	ns
t _{d(off)}	turn-off delay time		-	224	-	ns
t _f	fall time		-	117	-	ns
L _D	internal drain inductance	from drain lead 6 mm from package to centre of die; $T_j = 25 ^{\circ}\text{C}$	-	4.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drain	n diode					
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ C}$; see Figure 16	-	0.8	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	48	-	ns
Qr	recovered charge	$V_{DS} = 25 \text{ V}$	-	82	-	nC

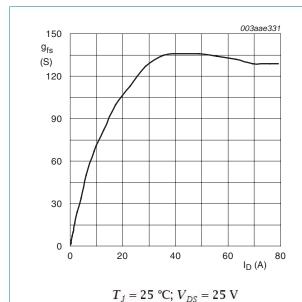


Fig 5. Forward transconductance as a function of drain current; typical values

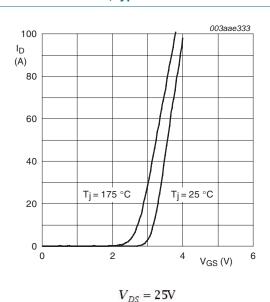
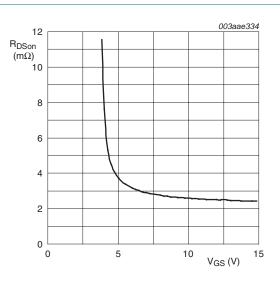


Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25$ °C; $I_D = 25$ A

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

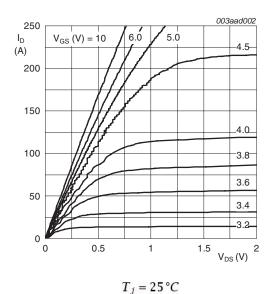


Fig 8. Output characteristics: drain current as a function of drain-source voltage; typical values

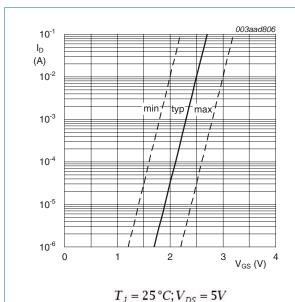


Fig 9. Sub-threshold drain current as a function of gate-source voltage

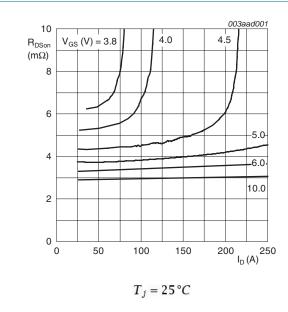


Fig 11. Drain-source on-state resistance as a function of drain current; typical values

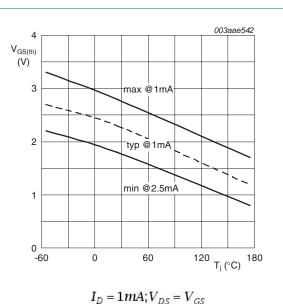


Fig 10. Gate-source threshold voltage as a function of junction temperature

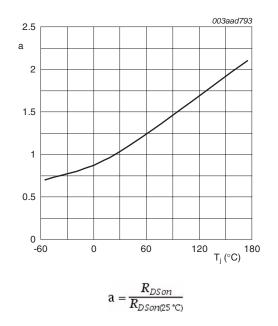


Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

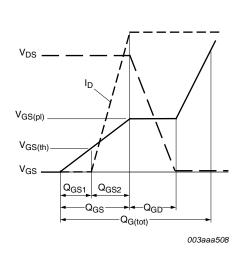
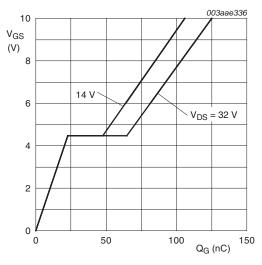


Fig 13. Gate charge waveform definitions



 $T_i = 25 \text{ C}; I_D = 25 \text{ A}$

Fig 14. Gate-source voltage as a function of gate charge; typical values

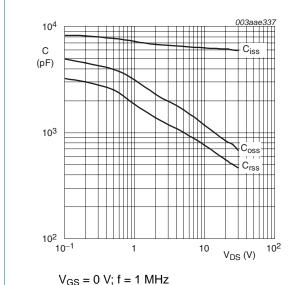
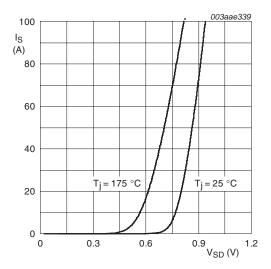


Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0 V$

Fig 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

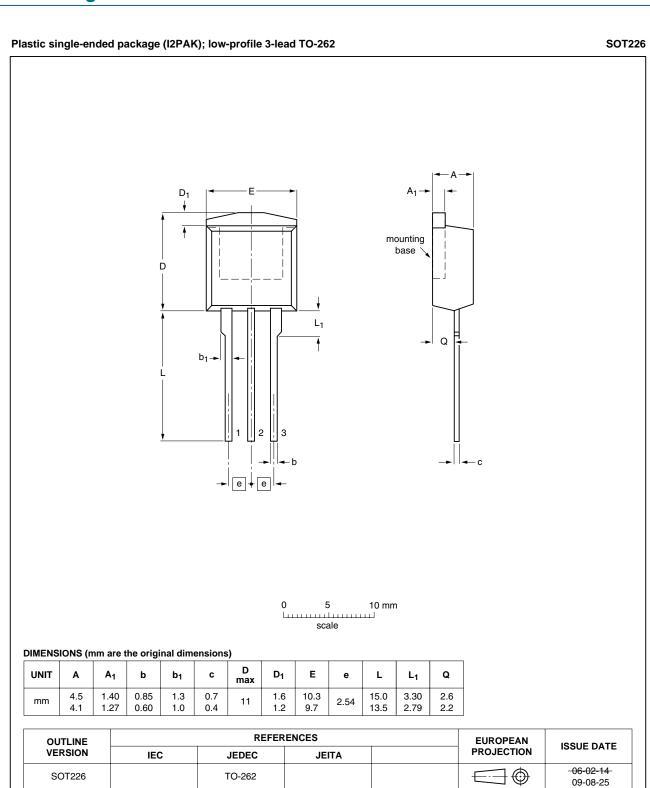


Fig 17. Package outline SOT226 (I2PAK)



8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK6E3R4-40C v.3	20101014	Product data sheet	-	BUK6E3R4-40C v.2
Modifications:	 Status change 	d from objective to product.		
BUK6E3R4-40C v.2	20100621	Objective data sheet	-	BUK6E3R4-40C v.1

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BUK6E3R4-40C

N-channel TrenchMOS intermediate level FET

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